

Issue Classification**Application/Control No.**

10604410

Applicant(s)/Patent Under Reexamination

DOYLE ET AL.

Examiner

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Art Unit

2613

ORIGINAL**INTERNATIONAL CLASSIFICATION****CLAIMED****NON-CLAIMED****CLASS****SUBCLASS****H****0****4****B****10 / 00****398**

166

CROSS REFERENCE(S)**CLASS****SUBCLASS (ONE SUBCLASS PER BLOCK)**

398

164

385

14

Danny Wai Lun Leung
(Assistant Examiner) (Date)

6/7/2007 (Date)

Total Claims Allowed:

8

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O.G. Print Claim(s) O.G. Print Figure
34 4